

FCC ID: 2ABU6-MTAG29

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

Antenna Type: PCB Antenna

Antenna Gain: 2.47 dBi

1M

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	1g SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	0.59	1.146	0±1	1.0	1.259	<5	0.39023	3.00	YES
	2.441	0.78	1.197	0±1	1.0	1.259	<5	0.39338	3.00	YES
	2.480	-1.73	0.671	-1±1	0.0	1.000	<5	0.31496	3.00	YES

2M

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	1g SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	0.61	1.151	0±1	1.0	1.259	<5	0.39023	3.00	YES
	2.441	0.82	1.208	0±1	1.0	1.259	<5	0.39338	3.00	YES
	2.480	-1.72	0.673	-1±1	0.0	1.000	<5	0.31496	3.00	YES

Conclusion:

For the max result : $0.39338 \leq 3.0$ for 1-g SAR, No SAR is required.


Signature:**Date:** 2022-01-18**NAME AND TITLE** (Please print or type): Alex /Manager

COMPANY (Please print or type): Shenzhen NTEK Testing Technology Co., Ltd./ 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen 518126 P.R. China